

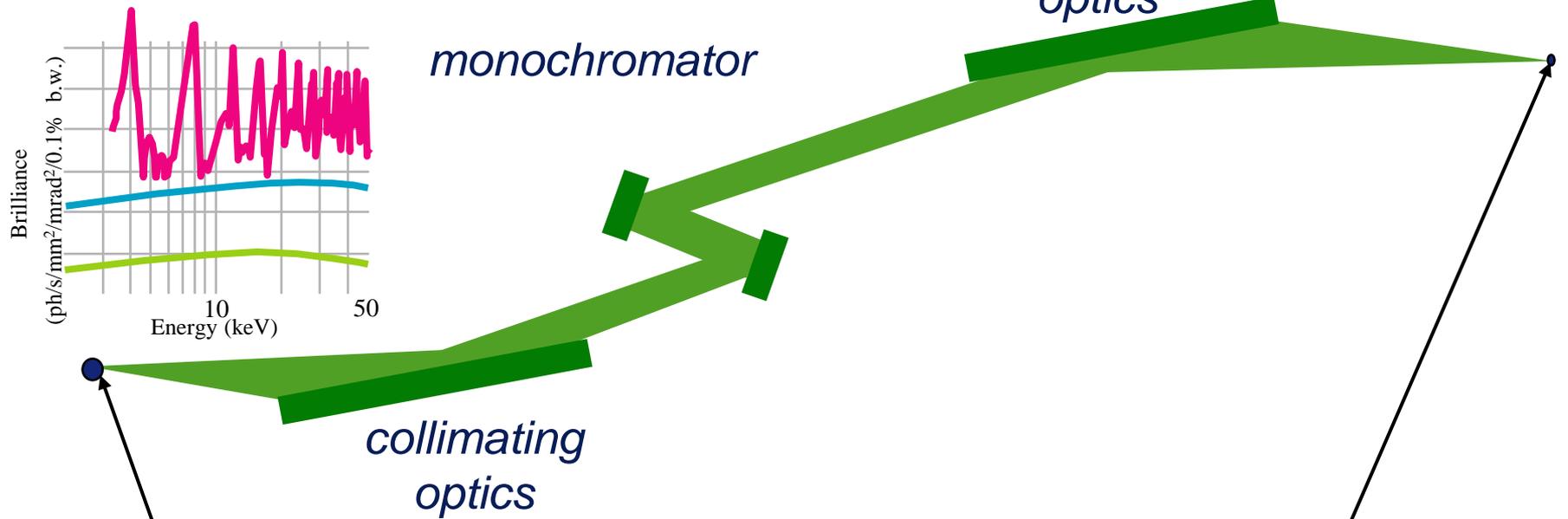
BEAMLINE OPTICS FOR SMALL ROUND BEAMS



- *Overview*
- *Impact of emittance reduction for X-ray optics*
- *Requirements*
- *Current limitations*

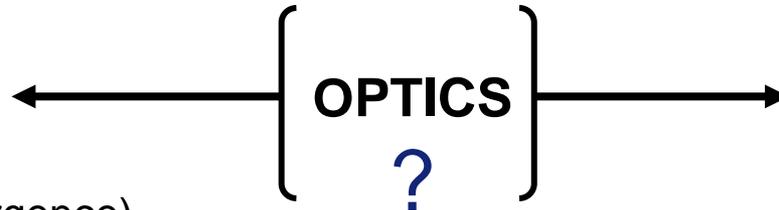
Ray Barrett
X-ray Optics Group Leader
Instrument Services & Development Division (ISDD)
ESRF

Typical optical geometry



Source

- spectrum ($\Delta E/E$)
- emittance (size x divergence)
- degree of spatial coherence
- brilliance (ph/s/mm²/mrad²/0.1%bw)
- polarisation (linear, circular, elliptic)

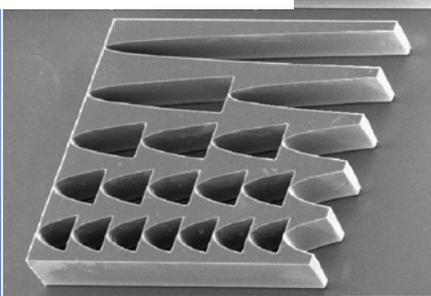


Sample

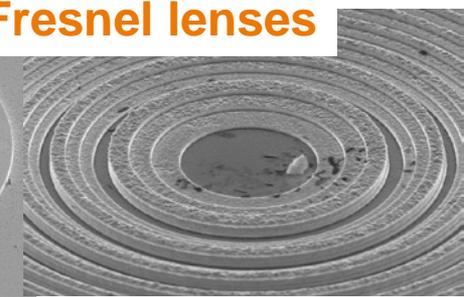
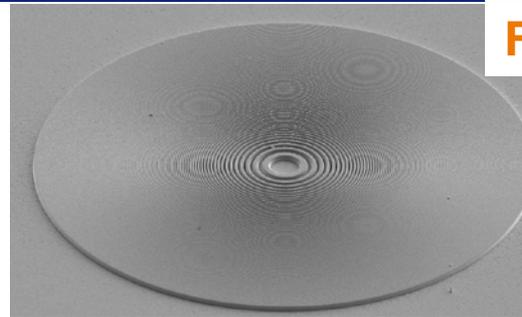
- beam size (μm)
- beam divergence (μrad)
- flux (ph/s)
- temporal coherence: $\Delta E/E$
- spatial coherence
- polarisation

X-RAY OPTICS

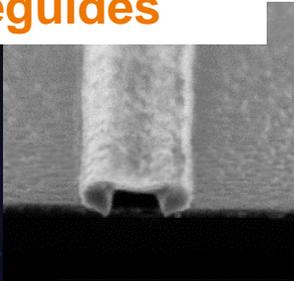
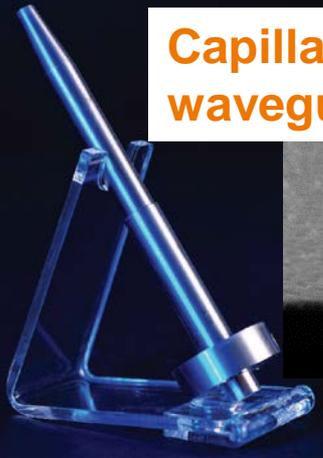
Refractive lenses



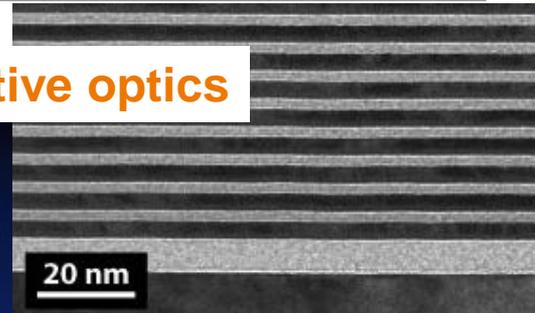
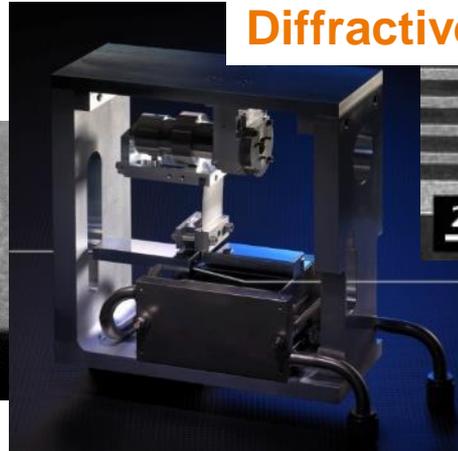
Fresnel lenses



Capillary optics waveguides



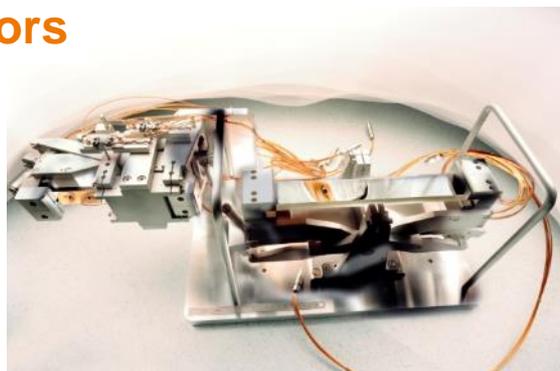
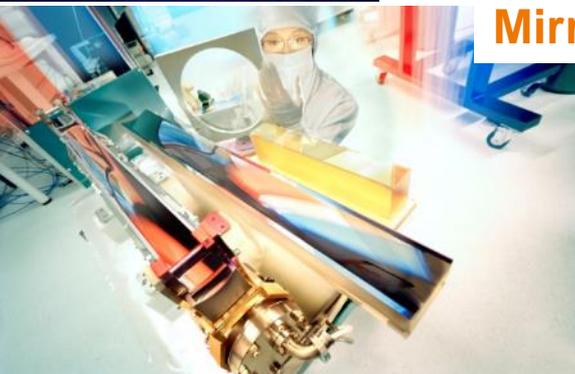
Diffractive optics



Filters



Mirrors



+ polarising optics,
interferometers, ...

imperfect optics increase emittance



The tolerable increase of emittance should be comparable to the stability of the source parameters (~ 10%)



- optical aberrations
- manufacturing errors
 - ✓ mirror slope errors
 - ✓ imperfect multilayer coatings
 - ✓ crystal imperfections (strain)
 - ✓ imperfect lenses
- mechanical & thermal deformations
- vibrations

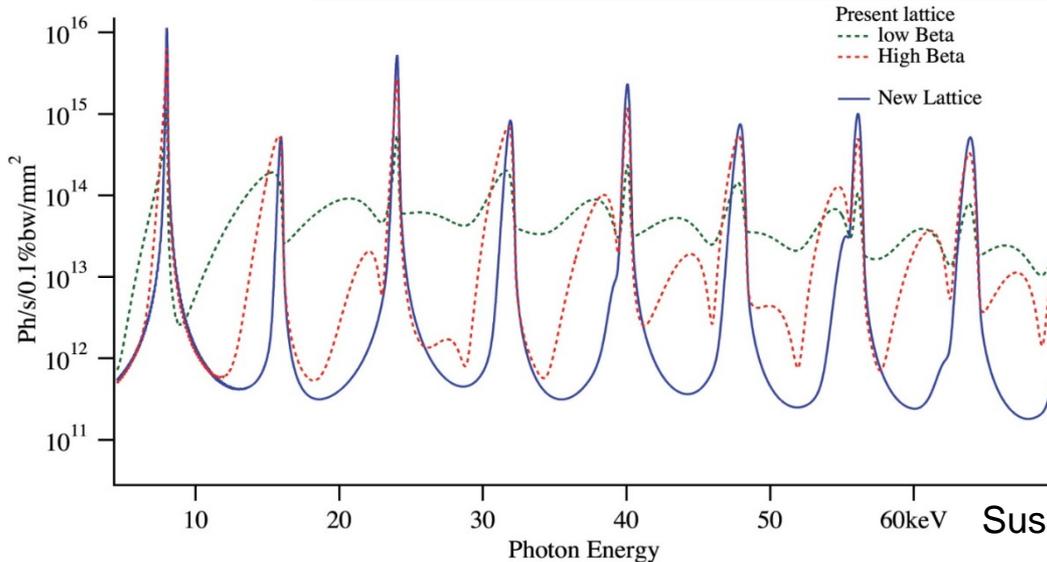
- ❖ high quality polishing
 - Slope & figure errors
- ❖ interfaces must be smooth and flat
 - micro-roughness, slope & figure errors
- ❖ use of perfect crystals
 - Silicon, Germanium, ...
- ❖ high accuracy lens profiling
 - mechanical tolerances, lithography...
- ❖ special mounting strategies
 - benders, supports, ...
- ❖ cooling strategies
 - water, LN2 cooling, ...

ESRF 'Extremely Brilliant Source'
EBS Project

ESRF X-RAY SOURCE PARAMETERS: CURRENT AND ESRF-EBS LATTICES

2m U18 undulator

Energy	Lattice	RMS size (μm)		RMS divergence (μrad)	
		H	V	H	V
10 keV	Current low β section	49	5.0	107	6.1
	Current high β section	410	4.9	11.5	6.1
	EBS lattice	30	5.1	7.4	6.1
50 keV	Current low β section	50	3.8	105.5	4.5
	Current high β section	410	3.8	11.2	4.5
	EBS lattice	30.3	4	6.1	4.5



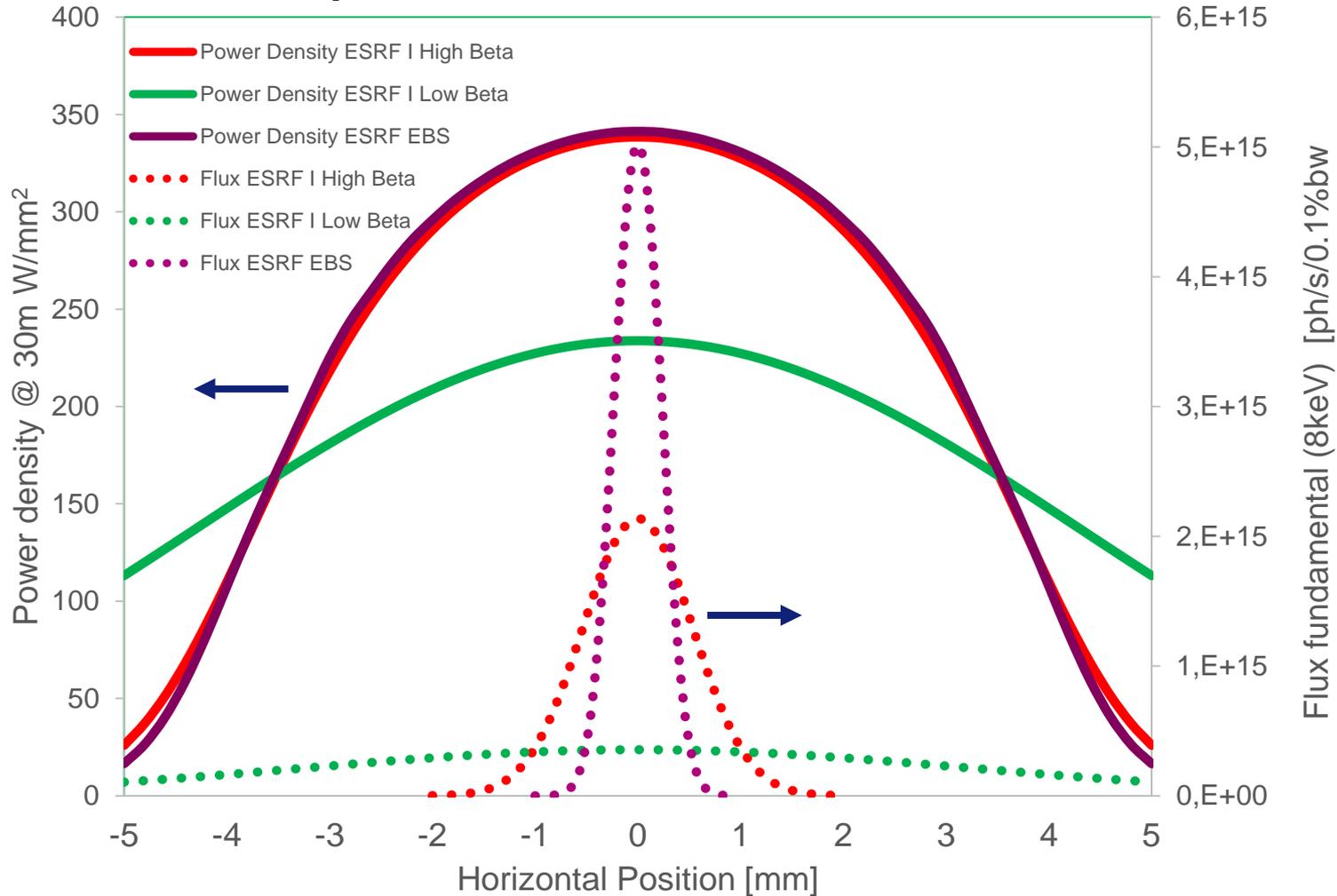
relatively little change

Improved spectral purity
 ~1.5x reduction in undulator
 peak width

Susini et al., *J. Synch. Rad.* **21**, (2014) 986–95

- **Reduction in horizontal beam divergence + source size**
 - ❖ Shorter mirrors (-> better quality)
 - ❖ Lower demagnification/smaller apertures: replace some mirrors by refractive lenses
- **Narrowing of energy width of undulator peaks**
 - ❖ Improved monochromator motor control for continuous energy scanning
- **Wavefront ('coherence')/ Emittance preservation**
 - ❖ Vertically little/no change, horizontal large improvements
 - ❖ Vertically deflecting reflective, monochromator optics still performance limiting (see later)
 - ❖ Requires improved quality of horizontally deflecting mirror (but shorter is generally better)
 - ❖ Replace some mirrors by refractive lenses
- **Heat Load?**

Spatial distribution of power density is primarily driven by the deflection parameter K of the undulator



**30m from source,
2 m CPMU18
K=1.67,
E=6.04GeV**

Peak power density comparable with existing lattice... but narrower emission cone

Characteristics of 2m-long, 18mm-period undulator at 10keV:

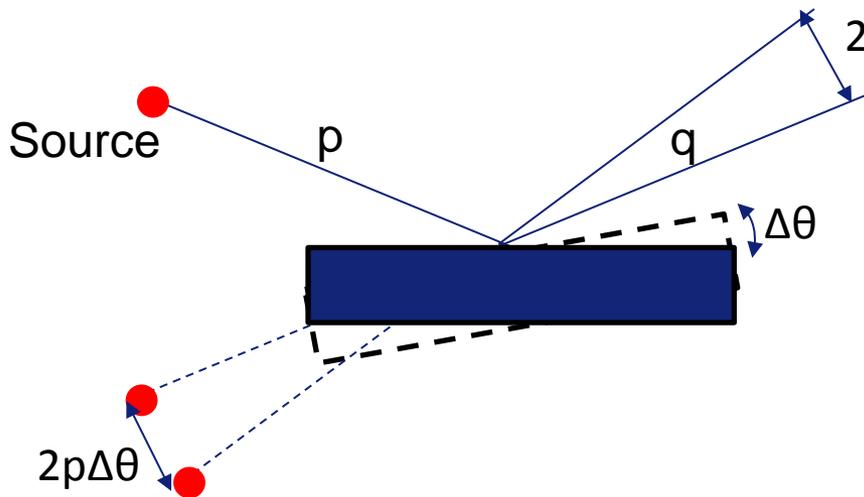
Lattice	RMS Photon beam size at 30m (μm)		Integrated Power over central cone (W)	Integrated Power in 0.1% BW (W)
	H	V		
Low β	3100	150	180	0.77
High β	530	150	42	0.77
EBS	220	150	17	0.77

'round' beam!

Integrated power: total power integrated over the RMS beamsize

Current cooling strategies will remain applicable 😊

Angular errors: slope errors, vibrations degrade apparent source size



angles \equiv source movement/magnification
(amplified by lever arm)

- Due to long lever arms at SR sources usually dominant cause of beam/effective source size degradation for both **static** and **dynamic systems**
- Resolution degradation (spatial, energy)
- Degraded wavefront

Aim for effective source size increase < 10%

e.g. Single mirror at 30m from low- β source (10keV):

ESRF 1996: $\sigma_v = 11\mu\text{m}$: $\Delta\theta_{\text{rms}} < 80$ nrad

$\sigma_h = 58\mu\text{m}$: $\Delta\theta_{\text{rms}} < 440$ nrad

ESRF 2014: $\sigma_v = 4.3\mu\text{m}$: $\Delta\theta_{\text{rms}} < 32$ nrad

$\sigma_h = 49\mu\text{m}$: $\Delta\theta_{\text{rms}} < 370$ nrad

EBS: $\sigma_v = 3.8\mu\text{m}$: $\Delta\theta_{\text{rms}} < 29$ nrad

$\sigma_h = 25\mu\text{m}$: $\Delta\theta_{\text{rms}} < 190$ nrad

Non-reflective optics similar issues –but smaller, lighter

Even in 1996 we needed 80 nrad angular stability – how did we survive?

- Optical quality and diversity much less developed (mirrors $\sim 5\mu\text{rad}$ rms slope errors, high energy zone plates had lower resolutions, no refractive lenses)
- Often other optical aberrations dominated (e.g. toroidal mirrors)
- Cooling technologies less well developed
- Vibrations/drifts at this level were secondary concerns
- Use horizontally deflecting mirrors (also helped for heat-load deformation) preferably double reflection on common support
- Put the optic closer to the source. ESRF limit is $\sim 30\text{m}$ + increased power density. Not possible for micro/nanofocusing optics – place on common support with sample.
- Use secondary source after (most) unstable optics
- Replace (some) double crystal monochromators with channel cut crystals

REQUIRED QUALITY OF X-RAY OPTICS (DIFFRACTION LIMITED FOCUSING)

Strehl ratio: > 80% (i.e. <20% of intensity outside spot)

Maréchal Criterion: rms wavefront error $\lambda/13$

Reflective Optics: Any deviation h from the ideal surface introduces a phase distortion φ . At grazing angle θ , $\varphi = (4\pi/\lambda) \cdot h \cdot \sin\theta$

X-ray energy (keV)	Coating material	Incidence angle θ (mrad)	Figure specification σ (nm, rms)
8	Rhodium	6.0	1.0
20	Platinum	3.0	0.8
50	Multilayer (W/B ₄ C)	5.9	0.15

e.g. O. Hignette *et al.*, Proc. SPIE 4501:43–53. San Diego 2001

Refractive Optics: Cumulated thickness errors, t , of lenses introduce phase distortion φ . For material with $n=1-\delta-i\beta$, $\varphi = 2\pi\delta t/\lambda$

X-ray energy (keV)	Lens material	delta	Figure specification σ (nm, rms) (full stack)	Figure specification σ (nm, rms) (per lens *)
8	Be	5.3E-06	2200	980
20	Be	8.5E-07	5600	1000
50	Al	2.2E-07	8700	810

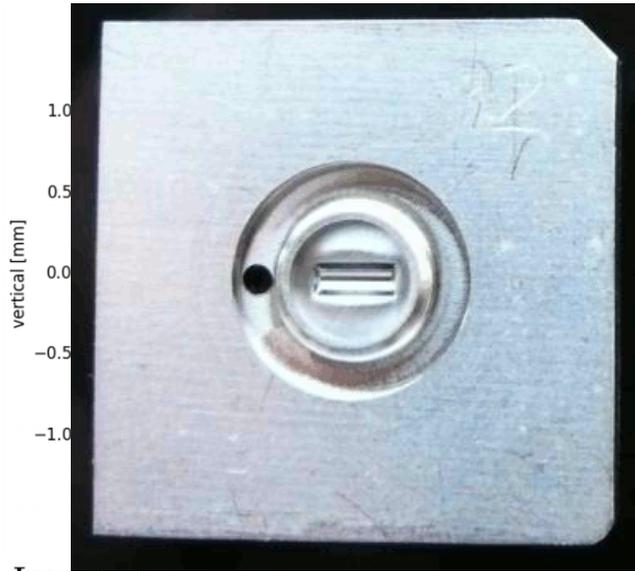
* Assumes focal length of 1m with lenses $R=50\mu\text{m}$

Fresnel Zone Plates: Zone placement accuracy $\sim 1/3$ zone width (3-4 nm!)

e.g. A.G. Michette, *Optical Systems for Soft X Rays*. Plenum Press, 1986

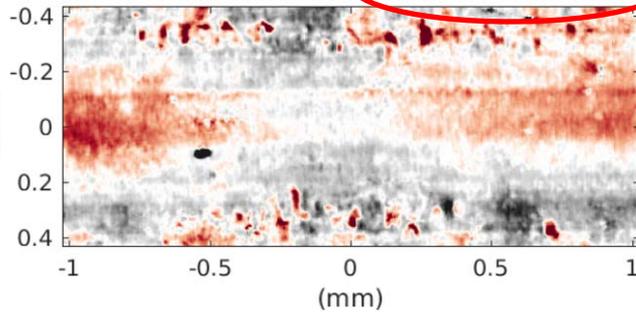
TYPICAL REFRACTIVE LENS QUALITY

Figure errors of 1D Be lens ($R_0 = 200 \mu\text{m}$)



Lens thickness error:

Lens thickness error - RMS = 1.4327 μm



Corrective 'glasses'

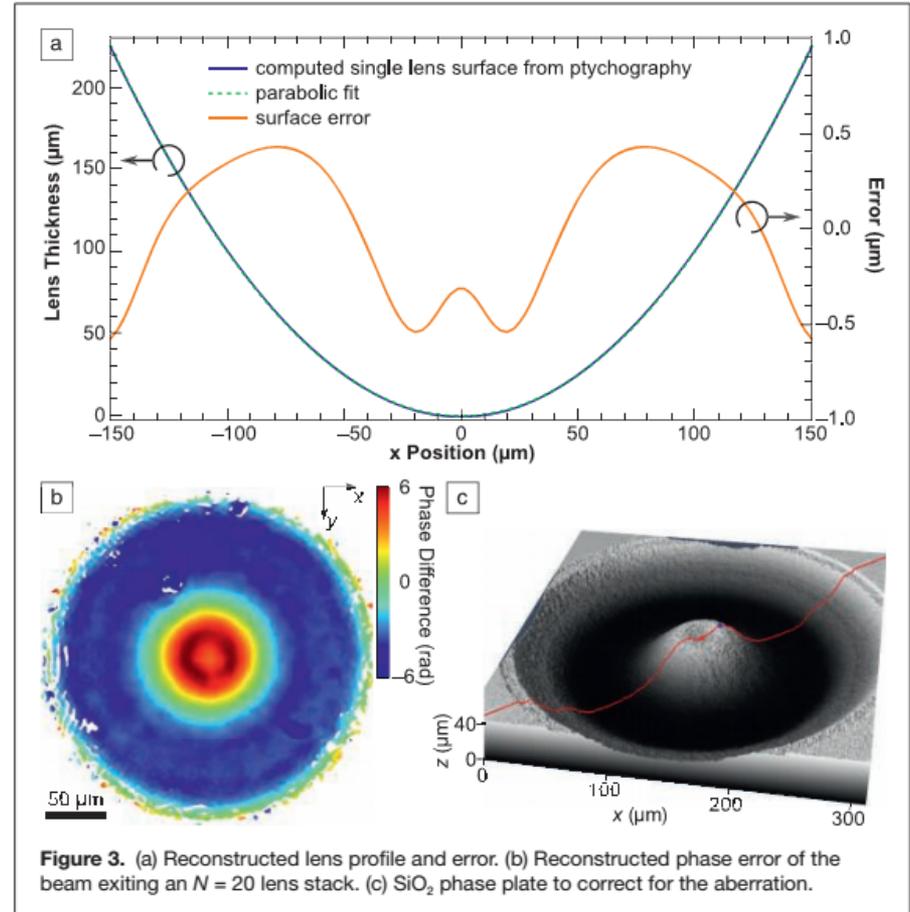


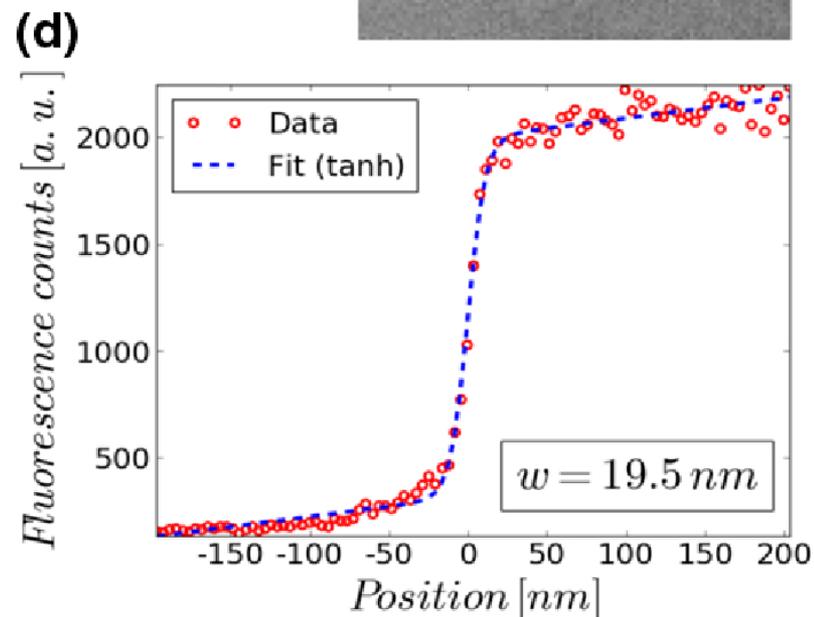
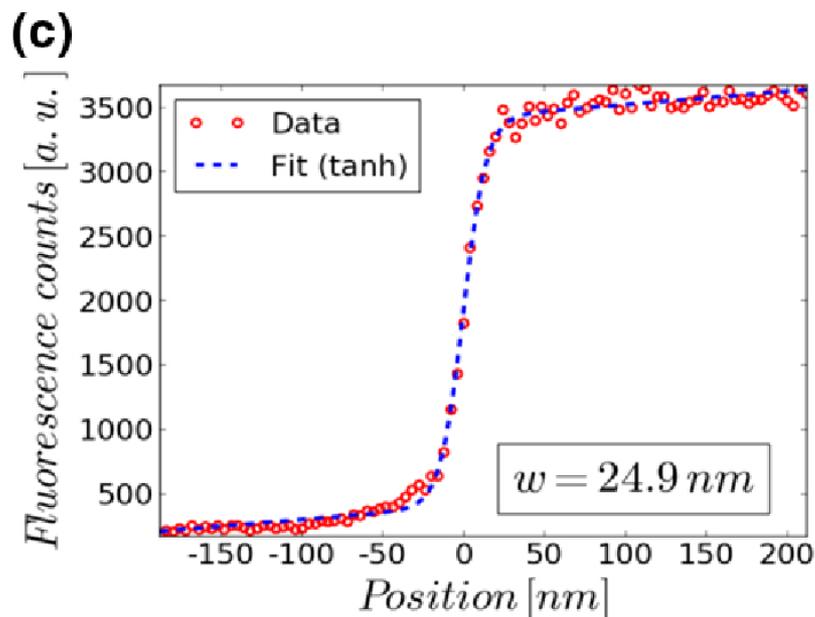
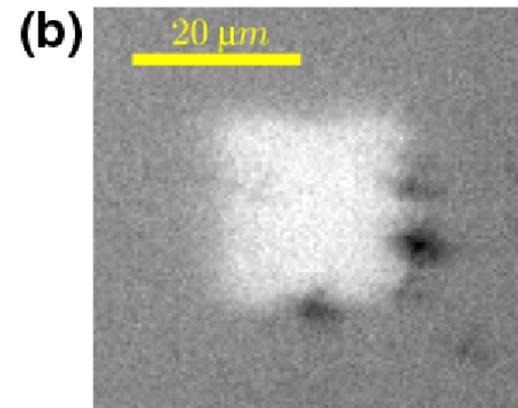
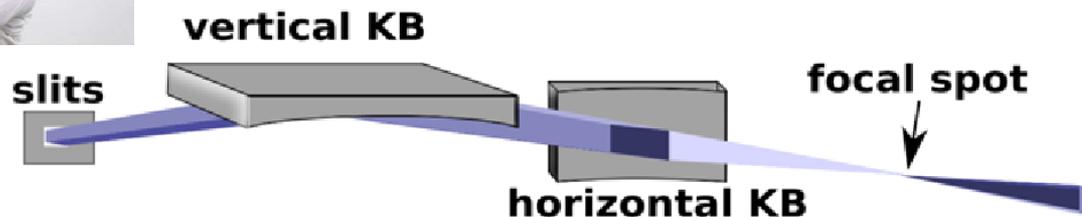
Figure 3. (a) Reconstructed lens profile and error. (b) Reconstructed phase error of the beam exiting an $N = 20$ lens stack. (c) SiO_2 phase plate to correct for the aberration.

F. Seiboth *et al*, Nat. Commun. 8, 14623 (2017)

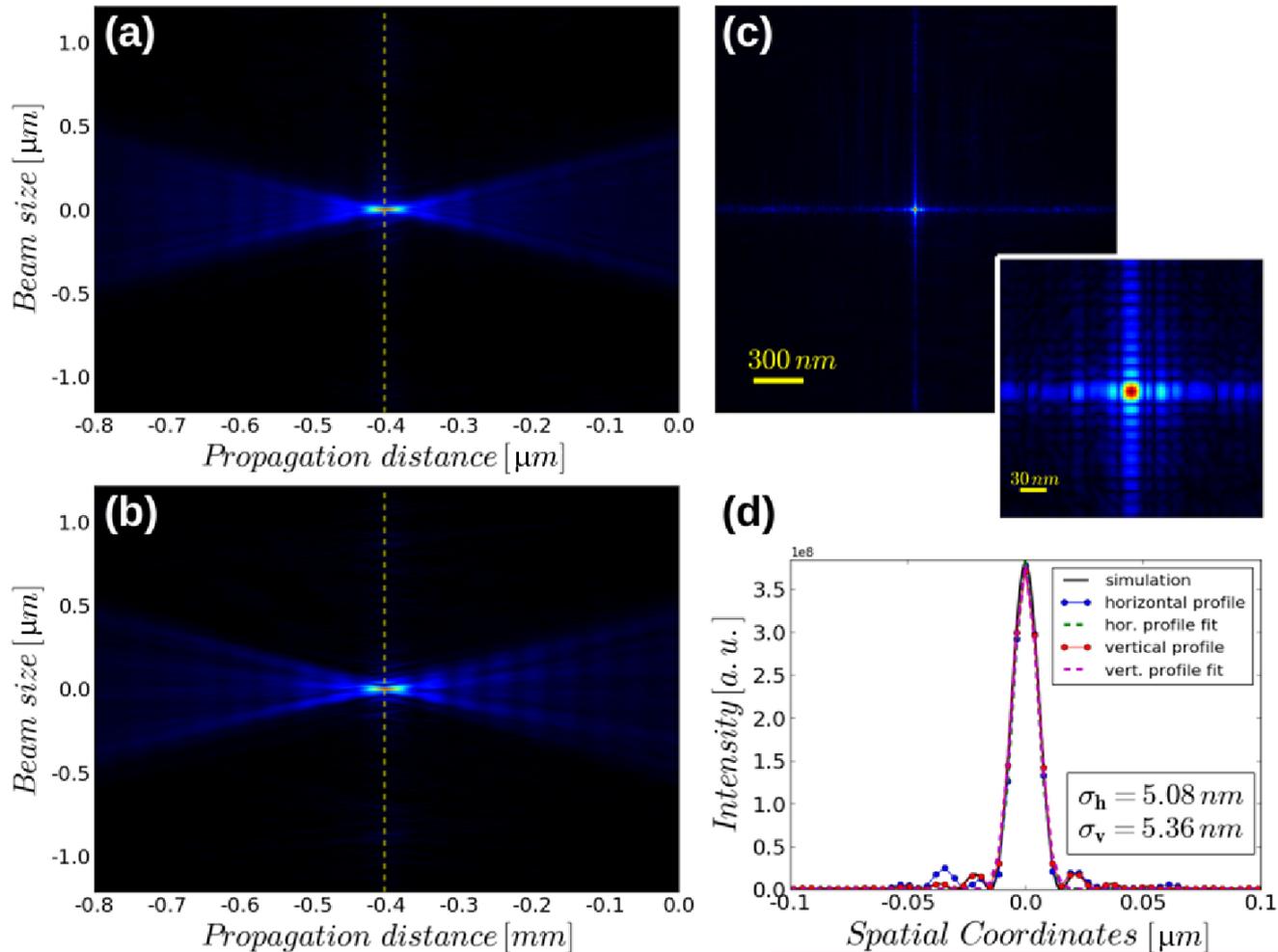
DIFFRACTION LIMITED FOCUSING AT 34KEV



Elliptical Cylinder Mirrors: Figure errors $< 1\text{ nm pv}$, roughness $< 1\text{ \AA}$
Multilayer coatings



BEAM PROFILE RECONSTRUCTION BY PTYCHOGRAPHY



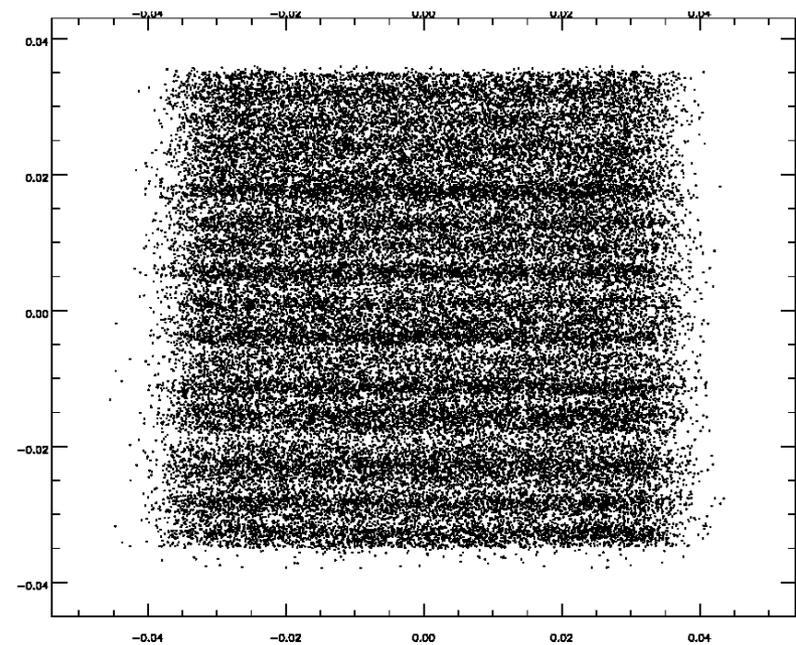
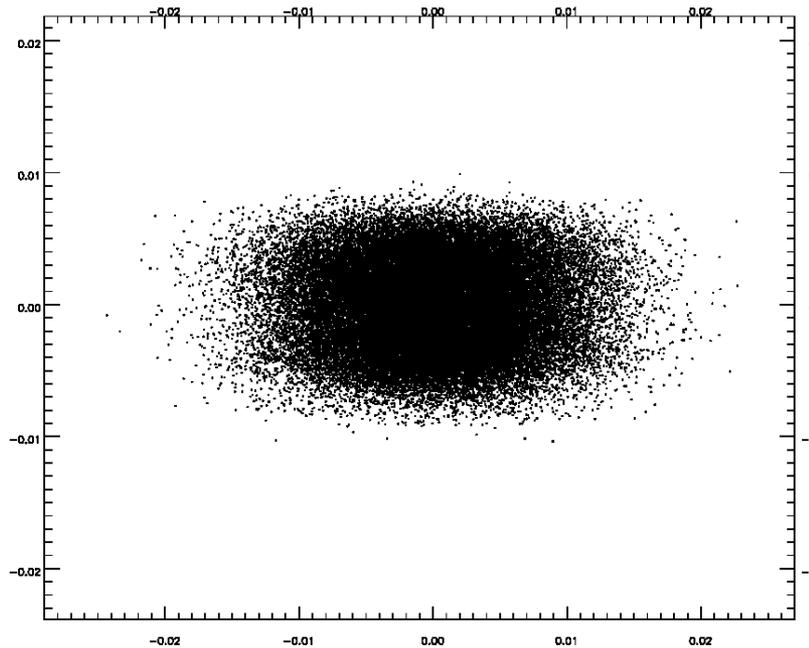
13 x 13 nm² fwhm beam size

- **Current mirror/substrate polishing quality:** slope errors < 100 nrad rms, < 1 nm p.v. but still performance limiting and few suppliers. Issues particularly in production of non-planar figures. Limits performance of ML systems too.
- **Crystal technologies:** energy resolutions ~ 0.5 meV (\rightarrow rocking curve < 85 nrad rms) polishing essentially ok but some distortions due to absorbed power. Diamond may still be of interest...
- **Refractive lenses:** Not perfect in terms of optical quality and numerical aperture – current activity to improve lens quality and develop diamond lenses
- **Diffraction lenses:** Tend to suffer from limited efficiency ($< 1\%$) at higher energies, Multilayer Laue lenses can overcome this but currently small apertures
- **Crystal monochromator technologies:** Particularly for applications requiring energy scanning (crystal parallelism $\sim 10\mu\text{rad}$ during energy scan)

Ray tracing simulations of mirror focused beam

in-focus

defocused



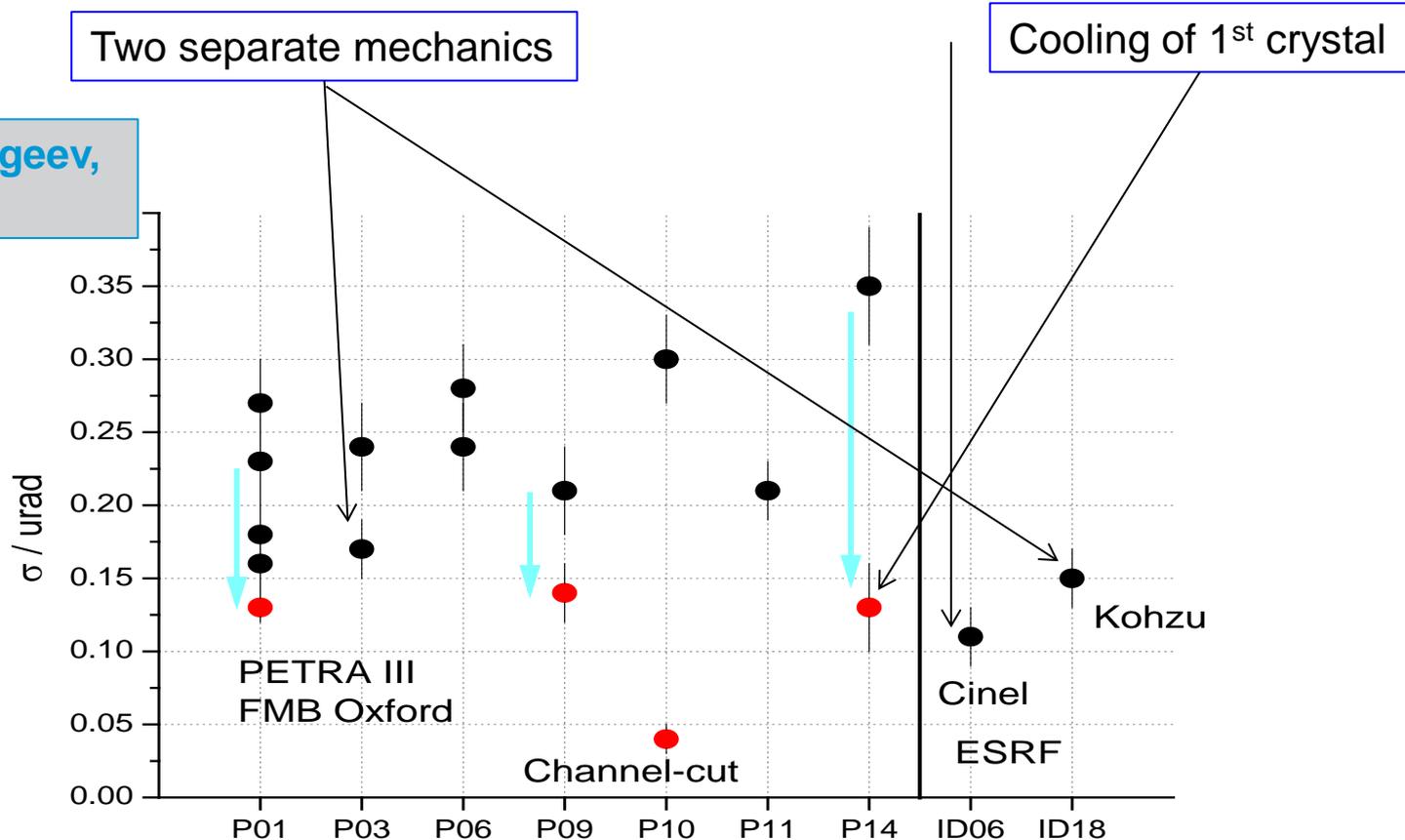
Actively corrected mirrors may be a partial solution

MONOCHROMATOR BEAM STABILITY

Sources aiming for high energy/spatial resolution and energy stability mostly experience limitations with current generation of commercial devices

e.g. crystal parallelism stability at fixed energy (measured in-situ):

Courtesy: Ilya Sergeev,
PETRA III

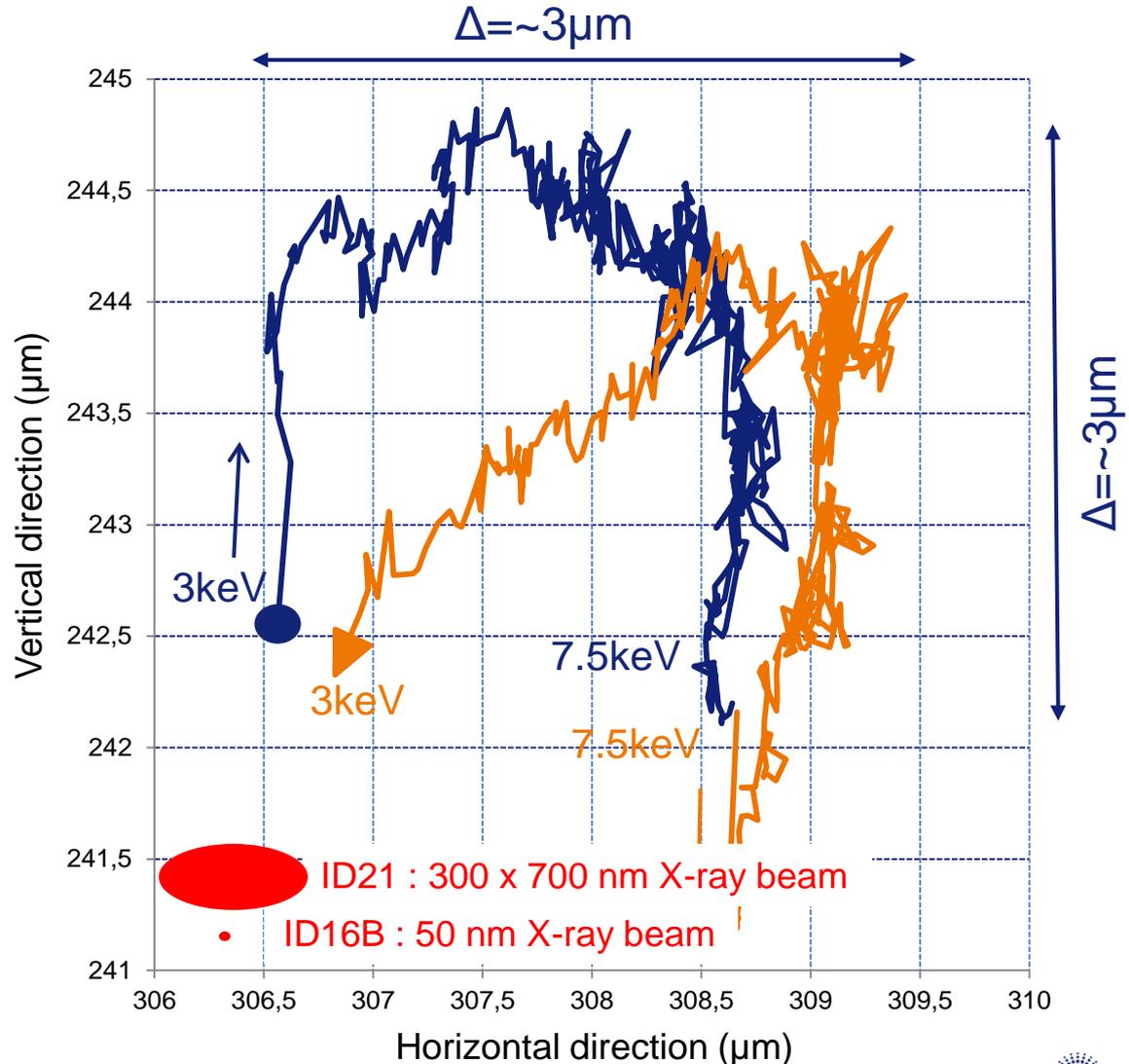


Some DCM systems give sub-50 nrad rms with LN2 cooling/beam but at fixed energy

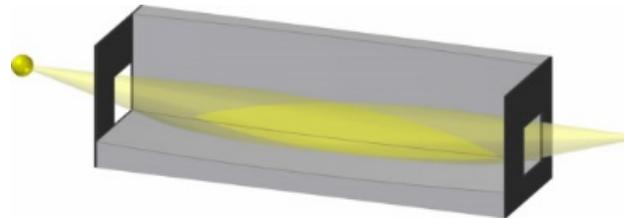
BEAM STABILITY DURING ENERGY SCAN – MORE CHALLENGING

Micro-beam trajectory in sample plane during an energy scan: *Courtesy M. Salome*

- Kohzu Si (111) monochromator
- KB focused micro-beam
- Energy range : 3 keV to 7.5 keV and back, 10 eV steps
- Angular range: 41.23 to 15.28 °
- Micro-beam position measured on fluorescence screen in KB focal plane with video-microscope in BPM mode
- $\Delta=3\mu\text{m}$ in focal plane corresponds to crystal parallelism variation $\sim 10\mu\text{rad}$

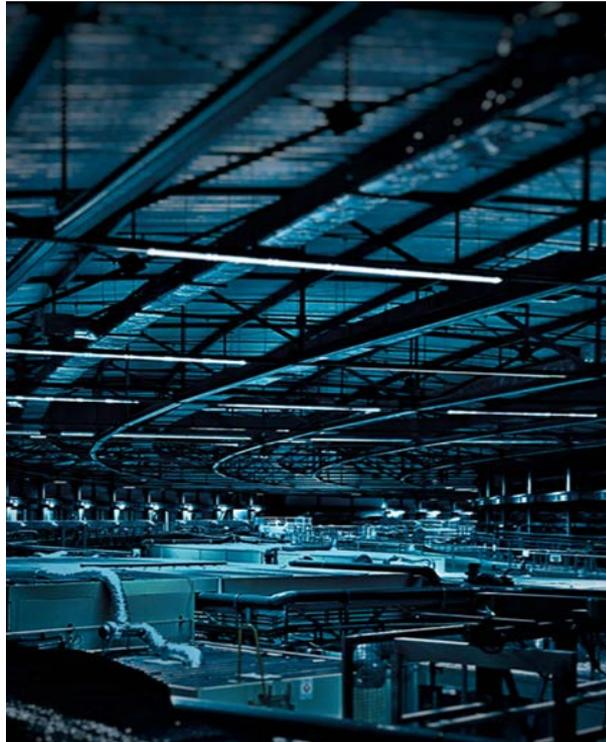


- Often mirrors used in horizontal deflecting geometry to mitigate the effects of ‘moderate’ mirror quality - this benefit would be lost (but relaxed for vertical deflection)
- Highest flux nanoprobe beams tend to be formed using KB mirror pairs which partially compensate the beam asymmetry. Montel mirrors as alternative?



- Increase of vertical source size would penalize beamlines aiming for highest energy resolutions and those aiming to maximise transverse coherence

- X-ray optics are constantly improving but do not yet preserve the source emittance
- An increase in the vertical emittance in a round beam scheme might relax some of the optical constraints but would not be desirable for certain applications



Thank you!
Merci!